Abstracts

The Effects of a Dielectric Capacitor Layer and Metallization on the Propagation Parameters of Coplanar Waveguide for MMIC (Short Papers)

R. Delrue, C. Seguinot, P. Pribetich and P. Kennis. "The Effects of a Dielectric Capacitor Layer and Metallization on the Propagation Parameters of Coplanar Waveguide for MMIC (Short Papers)." 1988 Transactions on Microwave Theory and Techniques 36.8 (Aug. 1988 [T-MTT]): 1285-1288.

The study of coupling phenomena between lines laid on semiconductor substrates in MMIC technologies and the determination of propagation effects on power FET require the characterization lines with micron transversal widths. For such lines, the influence of metallization thickness and dielectric cap layer on propagation properties can no longer be neglected. The purpose of this paper is to characterize these effects for the case of coplanar lines laid on semiconductor substrates.

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